

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

205109 US 20 DIV

SERIAL NO.

new appl.

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Paul ENQUIST

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Herewith

GROUP

not yet assigned

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
W	AA	5,387,807	02/07/95	Burhan BAYRAKTAROGU			
W	AB	5,943,577	08/24/99	Walter CONTRATA, et al.			
W	AC	5,856,209	01/05/99	Kenji IMANISHI			
W	AD	5,684,308	11/04/97	Michael L. LOVEJOY, et al.			
W	AE	5,648,294	07/15/97	Burhan BAYRAKTAROGU			
W	AF	5,552,617	09/03/96	Darrell G. HILL, et al.			
W	AG	5,512,496	04/30/96	Hin F. CHAU, et al.			
W	AH	5,468,658	11/21/95	Burhan BAYRAKTAROGU			
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W	AJ	5,249,074	09/28/93	Peter J. TOPHAM			
W	AK	5,239,550	08/24/93	Faquir C. JAIN			
W	AL	5,037,769	08/06/91	Masanori INADA, et al.			
W	AM	4,824,805	04/25/89	Yasutomo KAJIKAWA			
W	AN	4,751,201	06/14/88	Richard N. NOTTENBURG, et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
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	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

Examiner

Njm ✓ Ny

Date Considered

5-14-02

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

31002 U.S. PTO  
09/02/01  
04/02/01

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AQ	Submicron Lateral Scaling of Vertical-Transport Devices: Transferred-Substrate Bipolar Transistors and Schottky-Collector Tunnel Diodes; M. Rodwell, et al.; Invited Paper, 1997 ISA Ultrafast Electronics and Optoelectronics Conference
AR	A 277-GHz $f_{max}$ Transferred-Substrate Heterojunction Bipolar Transistor; B. Agarwal, et al.; IEEE Electron Device Letters, Vol. 18, No. 5, May 1997, pgs. 228-231
AS	Transferred Substrate Schottky-Collector Heterojunction Bipolar Transistors: First Results and Scaling Laws for High $f_{max}$ ; U. Bhattacharya, et al.; IEEE Electron Device Letters, Vol. 16, No. 8, August 1995, pgs. 357, 359
AT	A > 400 GHz $f_{max}$ Transferred-Substrate HBT Integrated Circuit Technology; R. Pullala, et al.; DRC 1997
AU	Deep Submicron Transferred-Substrate Heterojunction Bipolar Transistors; Q. Lee, et al.; DRC 1998
AV	170 GHz Transferred-Substrate Heterojunction Bipolar Transistor; U. Bhattacharya, et al.; Electronics Letters, 18th July 1996, Vol. 32, No. 15, pgs. 1405-6
AW	Transferred Substrate Heterojunction Bipolar Transistors; Dissertation by U. Bhattacharya, Nov. 27, 1996
AX	Digital Integrated Circuits in the Transferred-Substrate HBT Technology; Dissertation by R. Pullala, June 1998

EXAMINER

N/A ✓ N/A

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
NY	AA	5,318,916	06/07/94	ENQUIST ET AL.	—	—	
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	AU					
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